



The moment "I think" becomes "I know".
This is the moment we work for.

// TECHNOLOGY
MADE BY ZEISS

Invitation

ZEISS ORION User Meeting / 14th - 15th April 2015

We cordially invite you to the ZEISS ORION User Meeting in Empoli.

Location: Sala Conferenze c/o ASEV
via delle Fiascaie, 12
Empoli

For organisational reasons, we kindly ask you to **register until 6th March 2015** using the following link:

>> www.zeiss.com/tech-workshops

We have reserved a number of hotel rooms for a special group price. Price per night/person is 89,00 € breakfast included. Please indicate in the registration form if we should make a reservation for you. We only reserve the room for you. Payment has to be covered by yourself. Attendance at the workshop is free of charge to all participants.

HOTEL DA VINCI

Viale Togliatti, 157
50059 Sovigliana Vinci
<http://www.hotelda-vinci.it/albergo.htm>

We are happy to welcome you in Empoli.

Your ZEISS Microscopy Team



AGENDA

14th April 2015

Time	Program	
12:00	Welcome Fingerfood	
12:45	Nanott Nanotechnologies in Tuscany a bridge between Research and Industry	Giovanni Baldi Ce.Ri.Col - Centro Ricerche Colorobbia
13:15	HIM morphological characterization of nano engineered T cells	Arianna Signorini GRINT - EMPOLI
14:00	Third harmonic spectroscopy of single Au nanoantennas fabricated by Helium ion lithography	Martin Silies Carl von Ossietzky Universität Oldenburg
14:45	Coffee Break	
15:15	Advances in Applications using He/Ne Ion Microscopy	Bernhard Götze ZEISS
16:00	SIMS on the Helium Ion Microscope : a powerful tool for high-resolution high-sensitivity nano-analytics	Tom Wirtz Centre de Recherche Public - Gabriel Lippmann
16:45	End of day	
17:30	Visit Leonardo da Vinci museum	
20:00	Dinner	

15th April 2015

Time	Program	
09:00	Ion beam patterning using He, Ne and Ga ions in the area of nano-optics	Katja Höflich Helmholtz-Zentrum Berlin für Materialien und Energie GmbH
09:45	Helium Ion Microscope, a new characterization instrument in ENEA: overview of some experimental results	Marilena RE ENEA - Brindisi
10:30	Coffee Break	
11:00	Helium Ion Microscopy Characterization of Nanostructured Ge Layers	Massimo Bersani Fondazione Bruno Kessler
11:45	Multi 3D microscopy techniques to cover all scales	Christian Jäger ZEISS
12:30	Discussion	
13:00	Lunch	
14:00	End of Workshop	